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1 A new approach to evaluation of hot-carrier lifetime of ring oscillator (RO)

Jiong Zhang; Chu, S.-F.S.;

Electron Devices, IEEE Transactions on, Volume: 49, Issue: 9, Sept. 2002

Pages:1672 - 1674

[Abstract] [PDF Full-Text (226 KB)] IEEE JNL

2 AC hot-carrier degradation in a voltage controlled oscillator

Jiang, C.; Johnson, E.; Shaw, J.J.; Hu, C.;

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Pages:53 - 56

[Abstract] [PDF Full-Text (192 KB)] IEEE CNF

3 Effects of hot-carrier stress on the performance of the LC-tank CMOS oscillators

Naseh, S.; Deen, M.J.; Marinov, O.;

Electron Devices, IEEE Transactions on, Volume: 50, Issue: 5, May 2003

Pages:1334 - 1339

[Abstract] [PDF Full-Text (387 KB)] IEEE JNL

4 Hot-carrier and soft-breakdown effects on VCO performance

Enjun Xiao; Yuan, J.S.; Hong Yang;

Microwave Theory and Techniques, IEEE Transactions on, Volume: 50, Issue: 11, Nov. 2002

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5 RF circuit performance degradation due to hot carrier effects and soft breakdown

Enjun Xiao; Yuan, J.S.;
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Pages:I - 17-20 vol.1

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6 Hot carrier and soft breakdown effects on VCO performance

Enjun Xiao; Yuan, J.S.;
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7 Comparison of calculated AC to DC Hot Carrier lifetimes based on combined single MOST DC stress results and inverter simulations with AC stress measurements on single MOST's to check the duty factor approach

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10 Hot carrier and soft breakdown effects on VCO performance

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11 CMOS RF: (still) no longer an oxymoron

Lee, T.H.;
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12 Low power RFICs for receiver applications - design and performance issues*Deen, M.J.; Naseh, S.; Wai Leung Ngan; Jafferli, N.;*

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Pages:215 - 220

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13 Application of hot-carrier reliability simulation to memory and ASIC design*Lee, P.M.; Sato, H.;*

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14 Enhanced degradation of nMOSFET's under hot carrier stress at elevated temperatures due to the length of velocity saturation region*Hyunsang Hwang; Jung-Suk Goo; Hoyup Kwon; Hyungsoon Shin;*

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15 AC hot-carrier degradation in the super-100 MHz operation range*Yoshida, S.; Matsui, T.; Okuyama, K.; Kubota, K.;*

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